search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/787,314	BAYNE ET AL.	
Examiner	Art Unit	
Pia F. Tibbits	2838	

SEARCHED				
Class	Subclass	Date	Examiner	
320	116	7/2/2006	pt	
			:	

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
116	7/2/2006	PT			
	Subclass	Subclass Date			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		